

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/786,799	CHEN ET AL.	
Examiner	Art Unit	
Y. J. Han	2838	

	SEARCHED				
Class	Subclass	Date	Examiner		
323	313				
	314				
	316				
	274-281				
327	539				
	540				
323	317	3/17/2006	JH		
Search	updated	7/22/2006	/JH/		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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See sea	rch report	7/22/2006	/JH/		

SEARCH NO (INCLUDING SEARCH	TES STRATEGY	)
	DATE	EXMR
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